

AUTOMOTIVE GRADE

AUIRFR2407

HEXFET® Power MOSFET

Features

- Advanced Planar Technology
- Low On-Resistance
- Dynamic dV/dT Rating
- 175°C Operating Temperature
- Fast Switching

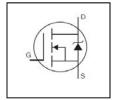
Description

applications.

- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Timax

Specifically designed for Automotive applications, this Stripe Planar design of HEXFET® Power MOSFETs utilizes the latest

- Lead-Free, RoHS Compliant
- Automotive Qualified *



| V _{DSS} | | 75V |
|---------------------|--------|--------------|
| R _{DS(on)} | typ. | 21.8mΩ |
| | max. | 26 mΩ |
| D (Silicon Li | mited) | 42A |



| G | D | S |
|------|-------|--------|
| Gate | Drain | Source |

processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other

| Page part number | Dookogo Tymo | Standard Pack | , | Orderable Part Number |
|------------------|--------------|--------------------|----------|-----------------------|
| Base part number | Package Type | Form | Quantity | Orderable Part Number |
| ALUDED2407 | D. Dok | Tube | 75 | AUIRFR2407 |
| AUIRFR2407 | D-Pak | Tape and Reel Left | 3000 | AUIRFR2407TRL |

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

| Symbol | Parameter | Max. | Units |
|---|---|--------------|-------|
| I _D @ T _C = 25°C | Continuous Drain Current, V _{GS} @ 10V (Silicon Limited) | 42 | |
| I _D @ T _C = 100°C | Continuous Drain Current, V _{GS} @ 10V (Silicon Limited) | 29 | Α |
| I _{DM} | Pulsed Drain Current ① | 170 | |
| P _D @T _C = 25°C | Maximum Power Dissipation | 110 | W |
| | Linear Derating Factor | 0.71 | W/°C |
| V_{GS} | Gate-to-Source Voltage | ± 20 | V |
| E _{AS} | Single Pulse Avalanche Energy (Thermally Limited) ② | 130 | mJ |
| I _{AR} Avalanche Current ① | | 25 | А |
| E _{AR} | Repetitive Avalanche Energy ① | 11 | mJ |
| dv/dt | Pead Diode Recovery dv/dt3 | 5.0 | V/ns |
| T_J | Operating Junction and | -55 to + 175 | |
| T _{STG} | Storage Temperature Range | | °C |
| | Soldering Temperature, for 10 seconds (1.6mm from case) | 300 | |

Thermal Resistance

| Symbol | Symbol Parameter | | Max. | Units |
|----------------|------------------------------------|--|------|-------|
| $R_{	heta JC}$ | Junction-to-Case ∅ | | 1.4 | |
| $R_{	heta JA}$ | Junction-to-Ambient (PCB Mount) ® | | 50 | °C/W |
| $R_{	heta JA}$ | Junction-to-Ambient | | 110 | |

HEXFET® is a registered trademark of Infineon.

2015-11-23

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

| | Parameter | Min. | Тур. | Max. | Units | Conditions |
|---------------------------------|--------------------------------------|------|-------|------|-----------|---|
| $V_{(BR)DSS}$ | Drain-to-Source Breakdown Voltage | 75 | | | V | $V_{GS} = 0V, I_D = 250\mu A$ |
| $\Delta V_{(BR)DSS}/\Delta T_J$ | Breakdown Voltage Temp. Coefficient | | 0.078 | | V/°C | Reference to 25°C, I _D = 1mA |
| R _{DS(on)} | Static Drain-to-Source On-Resistance | | 21.8 | 26.0 | $m\Omega$ | $V_{GS} = 10V, I_D = 25A $ ④ |
| $V_{GS(th)}$ | Gate Threshold Voltage | 2.0 | | 4.0 | V | $V_{DS} = V_{GS}$, $I_D = 250\mu A$ |
| gfs | Forward Trans conductance | 27 | | | S | $V_{DS} = 25V, I_{D} = 25A $ ④ |
| ı | Drain to Source Lookage Current | | | 25 | μA | $V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V}$ |
| I _{DSS} | Drain-to-Source Leakage Current | | | 250 | μΑ | $V_{DS} = 60V, V_{GS} = 0V, T_{J} = 150^{\circ}C$ |
| | Gate-to-Source Forward Leakage | | | 200 | n ^ | $V_{GS} = 20V$ |
| I _{GSS} | Gate-to-Source Reverse Leakage | | | -200 | nA | $V_{GS} = -20V$ |

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

| | Total Cata Channa | 7.4 | 440 | | 1 - 054 |
|------------------|------------------------------|-----------|-----|----|--|
| Q_g | Total Gate Charge | 74 | 110 | | I _D = 25A |
| Q_{gs} | Gate-to-Source Charge | 13 | 19 | nC | $V_{DS} = 60V$ |
| Q_{gd} | Gate-to-Drain Charge | 22 | 34 | | V _{GS} = 10V4 |
| $t_{d(on)}$ | Turn-On Delay Time | 16 | | | $V_{DD} = 38V$ |
| t _r | Rise Time | 90 | | | I _D = 25A |
| $t_{d(off)}$ | Turn-Off Delay Time | 65 | | ns | $R_G = 6.8\Omega$ |
| t _f | Fall Time | 66 | | | V _{GS} = 10V4 |
| L _D | Internal Drain Inductance | 4.5 | | | Between lead, 6mm (0.25in.) |
| L _S | Internal Source Inductance | 7.5 | | | from package and center of die contact |
| C _{iss} | Input Capacitance | 2400 | | | $V_{GS} = 0V$ |
| Coss | Output Capacitance | 340 | | | V _{DS} = 25V |
| C _{rss} | Reverse Transfer Capacitance | 77 | | _ | f = 1.0MHz, See Fig. 5 |
| C _{oss} | Output Capacitance | 15700 | | pF | $V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$ |
| C _{oss} | Output Capacitance | 220 | | | $V_{GS} = 0V, V_{DS} = 60V, f = 1.0MHz$ |
| Coss eff. | Effective Output Capacitance | 220 | | | V_{GS} = 0V, V_{DS} = 0V to 60V |

Diode Characteristics

| | Parameter | Min. | Тур. | Max. | Units | Conditions |
|-----------------|--|-----------|--|------|-------|--|
| I _S | Continuous Source Current (Body Diode) | | | 42 | | MOSFET symbol showing the |
| I _{SM} | Pulsed Source Current (Body Diode) ① | | | 170 | | integral reverse p-n junction diode. |
| V_{SD} | Diode Forward Voltage | | | 1.3 | V | $T_J = 25^{\circ}C, I_S = 25A, V_{GS} = 0V $ ④ |
| t _{rr} | Reverse Recovery Time | | 100 | 150 | ns | $T_J = 25^{\circ}C$, $I_F = 25A$ |
| Q_{rr} | Reverse Recovery Charge | | 400 | 600 | nC | di/dt = 100A/μs④ |
| t _{on} | Forward Turn-On Time | Intrinsio | Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D) | | | |

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- $^{\circ}$ V_{DD} = 25V, starting T_J = 25°C, L = 0.42mH, R_G = 25 Ω , I_{AS} = 25A
- $\label{eq:local_local_local_local} \ensuremath{\Im} \quad I_{SD} \leq 25A, \ di/dt \leq 290A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- \circ C_{oss eff} is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

 $\ \ \,$ $\ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \ \,$ $\ \,$ $\ \,$ $\ \,$ $\ \,$ $\ \,$ $\ \,$ $\ \,$ $\ \,$ $\ \,$ $\ \,$ $\ \,$ $\$



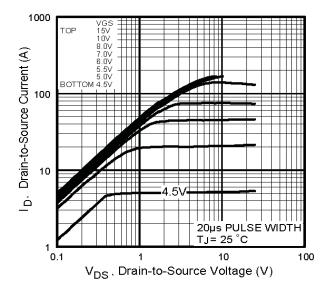


Fig. 1 Typical Output Characteristics

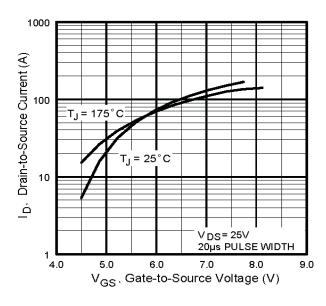


Fig. 3 Typical Transfer Characteristics

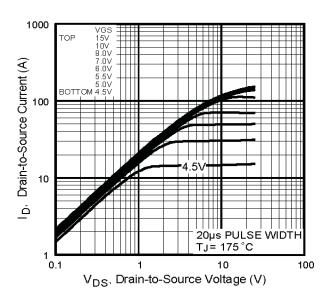


Fig. 2 Typical Output Characteristics

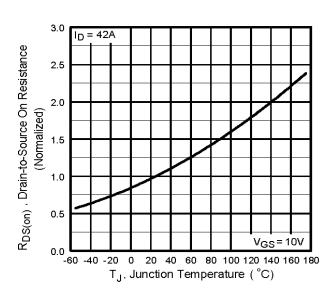


Fig. 4 Normalized On-Resistance Vs. Temperature



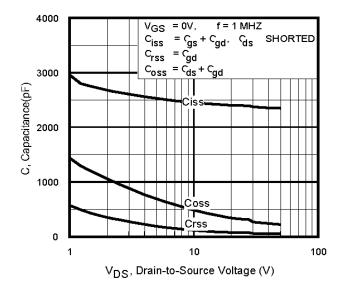


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

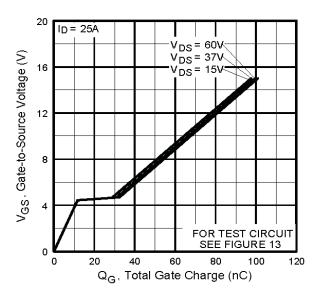


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

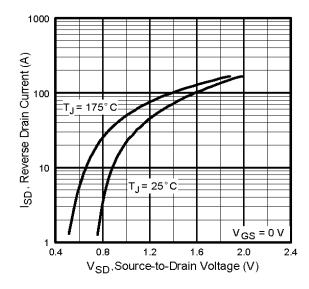


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

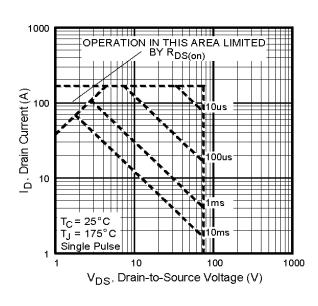


Fig 8. Maximum Safe Operating Area

4



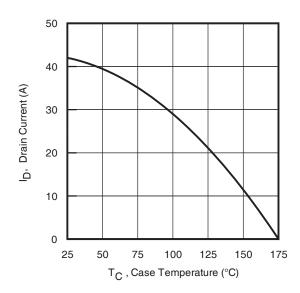


Fig 9. Maximum Drain Current Vs. Case Temperature

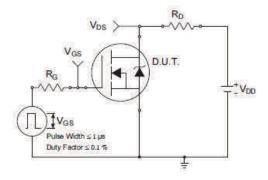


Fig 10a. Switching Time Test Circuit

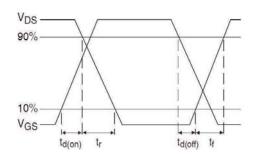


Fig 10b. Switching Time Waveforms

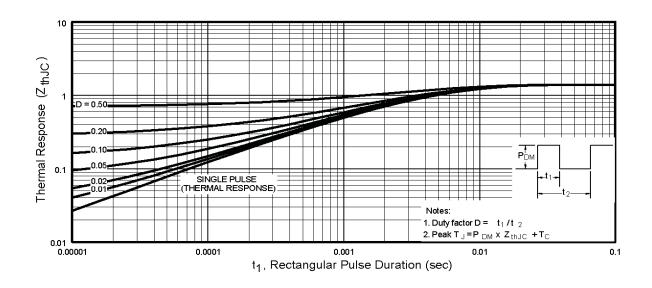


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



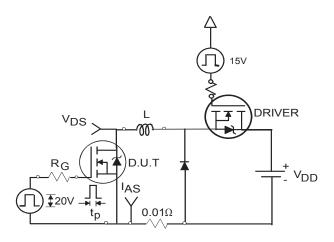


Fig 12a. Unclamped Inductive Test Circuit

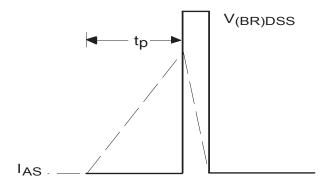


Fig 12b. Unclamped Inductive Waveforms

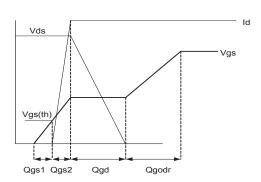


Fig 13a. Gate Charge Waveform

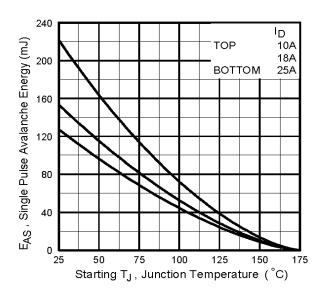


Fig 12c. Maximum Avalanche Energy vs. Drain Current

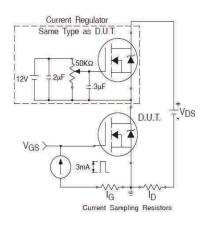
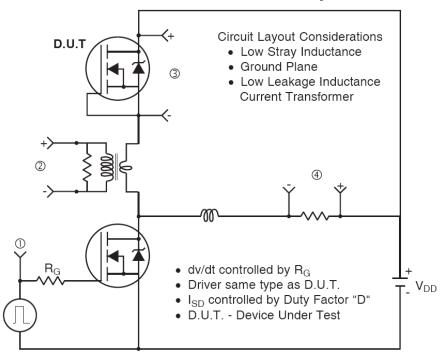


Fig 13b. Gate Charge Test Circuit

2015-11-23



Peak Diode Recovery dv/dt Test Circuit



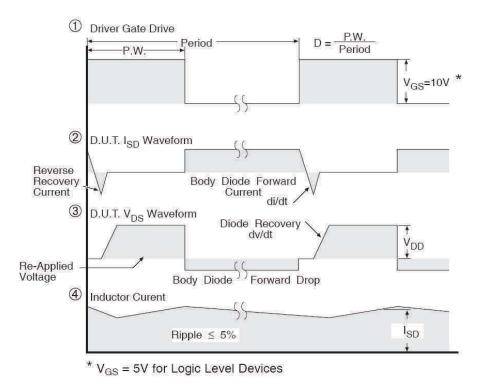
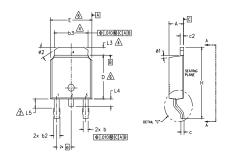


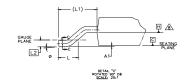
Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

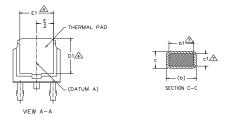


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- A- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- 6- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

| S | | | | | |
|--------|--------|-------|-------|------|--------|
| Y M | | DIMEN | SIONS | | Й |
| B | MILLIM | ETERS | INC | HES | O T |
| O L | MIN. | MAX. | MIN. | MAX. | E S |
| Α | 2.18 | 2.39 | .086 | .094 | |
| A1 | - | 0.13 | - | .005 | |
| b | 0.64 | 0.89 | .025 | .035 | |
| ь1 | 0.65 | 0.79 | .025 | .031 | 7 |
| b2 | 0.76 | 1.14 | .030 | .045 | |
| b3 | 4.95 | 5.46 | .195 | .215 | 4 |
| С | 0.46 | 0.61 | .018 | .024 | |
| c1 | 0.41 | 0.56 | .016 | .022 | 7 |
| c2 | 0.46 | 0.89 | .018 | .035 | |
| D | 5.97 | 6.22 | .235 | .245 | 6 |
| D1 | 5.21 | - | .205 | - | 4 |
| Ε | 6.35 | 6.73 | .250 | .265 | 6 |
| E1 | 4.32 | - | .170 | - | 4 |
| е | 2.29 | BSC | .090 | BSC | |
| Н | 9.40 | 10.41 | .370 | .410 | |
| L | 1.40 | 1.78 | .055 | .070 | |
| L1 | 2.74 | BSC | .108 | REF. | |
| L2 | 0.51 | BSC | .020 | BSC | |
| L3 | 0.89 | 1.27 | .035 | .050 | 4 |
| L4 | - | 1.02 | - | .040 | |
| L5 | 1.14 | 1.52 | .045 | .060 | 3 |
| ø | 0, | 10° | 0, | 10° | |
| ø1 | 0, | 15° | 0, | 15* | |
| ø2 | 25* | 35° | 25* | 35* | |

LEAD ASSIGNMENTS

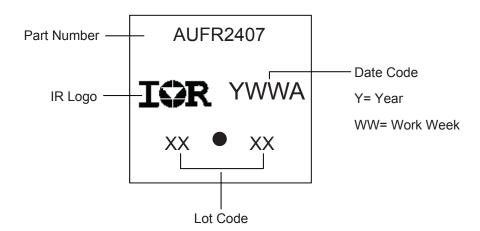
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR 3.- EMITTER
- 4.- COLLECTOR

D-Pak (TO-252AA) Part Marking Information

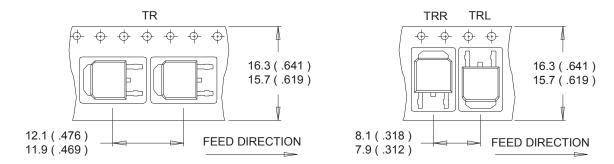


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

2015-11-23

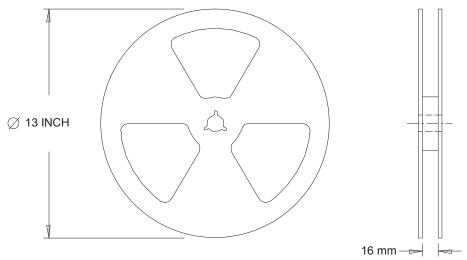


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

| ~uaou | | | | | | |
|----------------------|----------------------------|---|--------------|--|--|--|
| | | Automotive (per AEC-Q101) | | | | |
| | | Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level. | | | | |
| | | D-Pak | MCI 1 | | | |
| Woisture | Moisture Sensitivity Level | | MSL1 | | | |
| | Manhina Madal | Class M4 (+/-500V) [†] | | | | |
| | Machine Model | | AEC-Q101-002 | | | |
| E0D | Harris Dada Madal | Class H1C (+/-2000V) [†] | | | | |
| ESD | Human Body Model | AEC-Q101-001 | | | | |
| | Observad Davis a Madal | Class C5 (+/-2000V) [†] | | | | |
| Charged Device Model | | AEC-Q101-005 | | | | |
| RoHS Compliant | | | Yes | | | |
| | | | | | | |

[†] Highest passing voltage.

Revision History

| Date | Comments | | |
|----------|---|--|--|
| 11/23/15 | Updated datasheet with corporate template | | |
| 11/23/13 | Corrected ordering table on page 1. | | |

Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2015 All Rights Reserved.

IMPORTANT NOTICE

The information given in this document shall in <u>no event</u> be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may <u>not</u> be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.